

Search Notes

Application No.

10/065,552

Examiner

Wai-Sing Louie

Applicant(s)

SAWADA ET AL.

Art Unit

2814

SEARCHED

Class	Subclass	Date	Examiner
438	14-18	11/15/2004	WSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Wafer testing and measurement, carrier concentration, profiling, capacitance, voltage	11/15/2004	WSL